



## Description

The HSH3129 is the high cell density trenched P-ch MOSFETs, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.

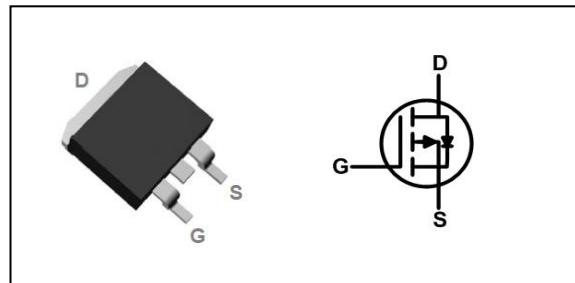
The HSH3129 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

## Product Summary

$V_{DS}$	-30	V
$R_{DS(ON),typ}$	1.4	$m\Omega$
$I_D$	-220	A

- Super Low Gate Charge
- 100% EAS Guaranteed
- Green Device Available
- Excellent CdV/dt effect decline
- Advanced high cell density Trench technology

## TO-263 Pin Configuration



## Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	-30	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ -10V^{1,6}$	-220	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ -10V^{1,6}$	-140	A
$I_{DM}$	Pulsed Drain Current <sup>2</sup>	-880	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	1350	mJ
$I_{AS}$	Avalanche Current	-95	A
$P_D @ T_C = 25^\circ C$	Total Power Dissipation <sup>4</sup>	200	W
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C

## Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction-ambient <sup>1</sup> (Steady State)	---	62	°C/W
$R_{\theta JC}$	Thermal Resistance Junction-case <sup>1</sup>	---	0.85	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$ , unless otherwise noted)**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$\text{V}_{\text{GS}}=0\text{V}$ , $\text{I}_D=-250\mu\text{A}$	-30	---	---	V
$\text{R}_{\text{DS(ON)}}$	Static Drain-Source On-Resistance <sup>2</sup>	$\text{V}_{\text{GS}}=-10\text{V}$ , $\text{I}_D=-30\text{A}$	---	1.4	1.8	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=-4.5\text{V}$ , $\text{I}_D=-20\text{A}$	---	1.8	2.4	$\text{m}\Omega$
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	$\text{V}_{\text{GS}}=\text{V}_{\text{DS}}$ , $\text{I}_D=-250\mu\text{A}$	-1.0	---	-2.5	V
$\text{I}_{\text{DSS}}$	Drain-Source Leakage Current	$\text{V}_{\text{DS}}=-30\text{V}$ , $\text{V}_{\text{GS}}=0\text{V}$ , $T_J=25^\circ\text{C}$	---	---	-1	$\text{uA}$
		$\text{V}_{\text{DS}}=-30\text{V}$ , $\text{V}_{\text{GS}}=0\text{V}$ , $T_J=125^\circ\text{C}$	---	---	-100	
$\text{I}_{\text{GSS}}$	Gate-Source Leakage Current	$\text{V}_{\text{GS}}=\pm 20\text{V}$ , $\text{V}_{\text{DS}}=0\text{V}$	---	---	$\pm 100$	nA
$\text{R}_g$	Gate resistance	$\text{V}_{\text{DS}}=0\text{V}$ , $\text{V}_{\text{GS}}=0\text{V}$ , $f=1\text{MHz}$		1.8		$\Omega$
$\text{Q}_g$	Total Gate Charge (-10V)	$\text{V}_{\text{DS}}=-15\text{V}$ , $\text{V}_{\text{GS}}=-10\text{V}$ , $\text{I}_D=-20\text{A}$	---	420	---	nC
$\text{Q}_{\text{gs}}$	Gate-Source Charge		---	48	---	
$\text{Q}_{\text{gd}}$	Gate-Drain Charge		---	62	---	
$\text{T}_{\text{d(on)}}$	Turn-On Delay Time	$\text{V}_{\text{DD}}=-15\text{V}$ , $\text{V}_{\text{GS}}=-10\text{V}$ , $\text{R}_g=3\Omega$ , $\text{I}_D=-10\text{A}$	---	17	---	ns
$\text{T}_r$	Rise Time		---	6	---	
$\text{T}_{\text{d(off)}}$	Turn-Off Delay Time		---	21	---	
$\text{T}_f$	Fall Time		---	39	---	
$\text{C}_{\text{iss}}$	Input Capacitance	$\text{V}_{\text{DS}}=-15\text{V}$ , $\text{V}_{\text{GS}}=0\text{V}$ , $f=1\text{MHz}$	---	25400	---	pF
$\text{C}_{\text{oss}}$	Output Capacitance		---	2580	---	
$\text{C}_{\text{rss}}$	Reverse Transfer Capacitance		---	2410	---	

**Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$\text{I}_s$	Continuous Source Current <sup>1,5</sup>	$\text{V}_G=\text{V}_D=0\text{V}$ , Force Current	---	---	-220	A
$\text{V}_{\text{SD}}$	Diode Forward Voltage <sup>2</sup>	$\text{V}_{\text{GS}}=0\text{V}$ , $\text{I}_s=-20\text{A}$ , $T_J=25^\circ\text{C}$	---	---	-1.2	V
$\text{t}_{\text{rr}}$	Reverse Recovery Time	$\text{I}_F=-20\text{A}$ , $d\text{I}/dt=100\text{A}/\mu\text{s}$ , $T_J=25^\circ\text{C}$	---	50	---	nS
$\text{Q}_{\text{rr}}$	Reverse Recovery Charge		---	120	---	nC

Note :

- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is  $\text{V}_{\text{DD}}=-30\text{V}$ ,  $\text{V}_{\text{GS}}=-10\text{V}$ ,  $L=0.5\text{mH}$ ,  $\text{I}_{\text{AS}}=-95\text{A}$
- 4.The power dissipation is limited by  $150^\circ\text{C}$  junction temperature
- 5.The data is theoretically the same as  $\text{I}_s$  and  $\text{I}_{\text{DM}}$  , in real applications , should be limited by total power dissipation
- 6.The maximum current rating is package limited.



### Typical Characteristics

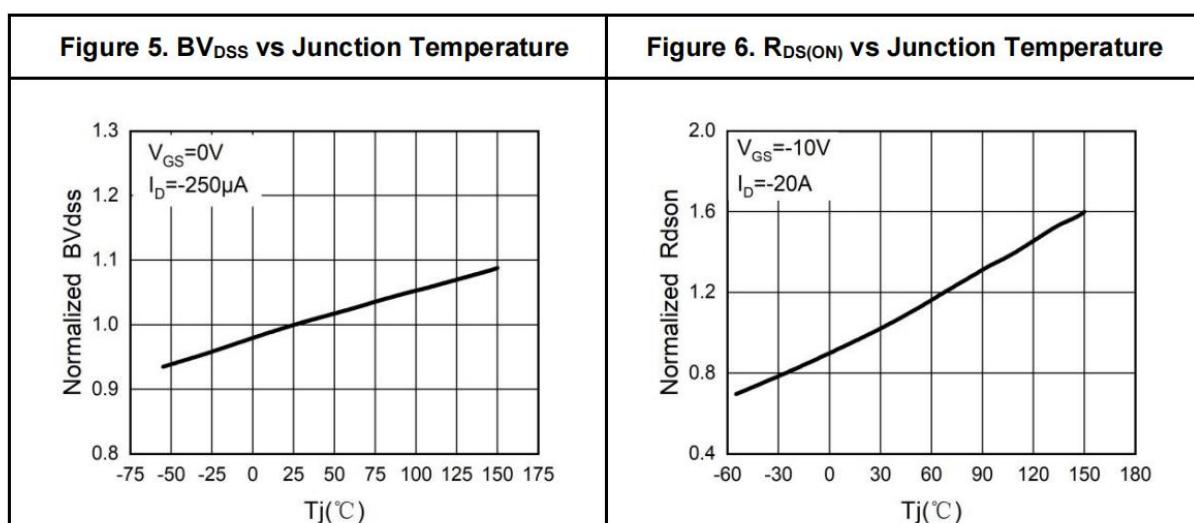
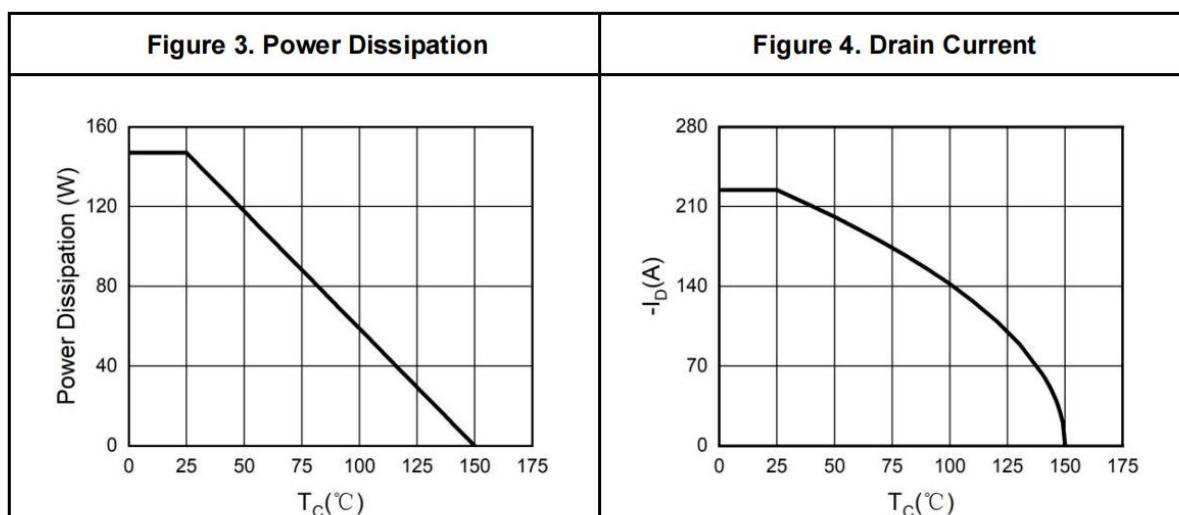
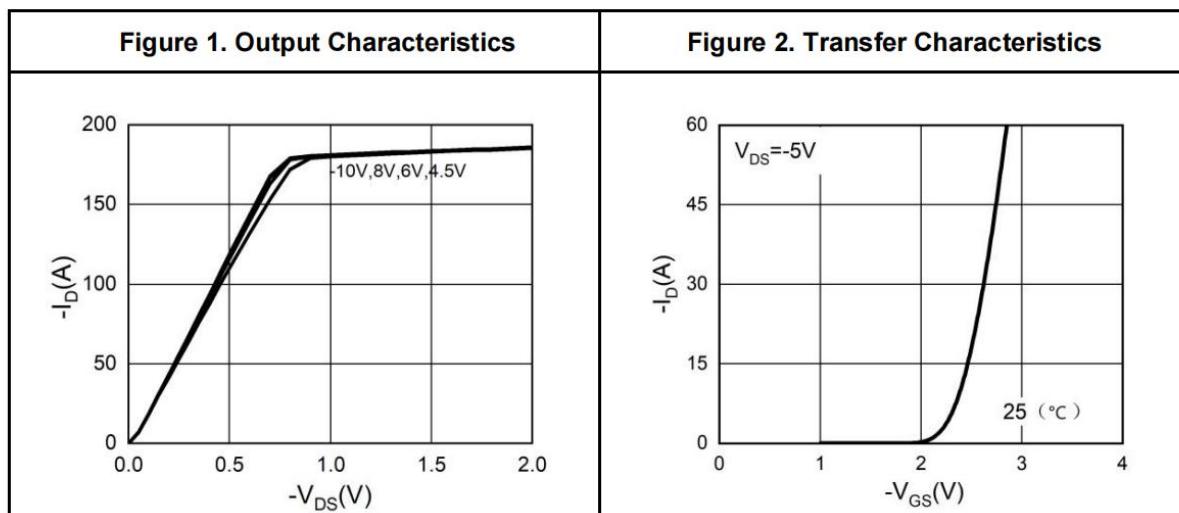




Figure 7. Gate Charge Waveforms

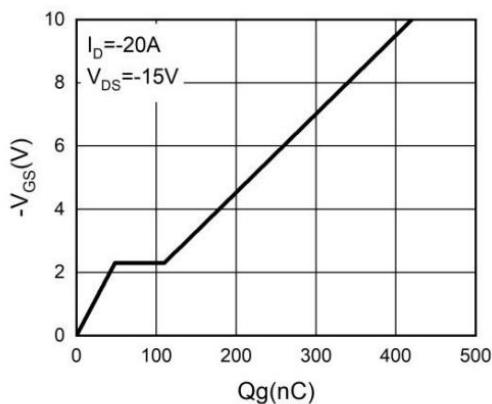


Figure 8. Capacitance

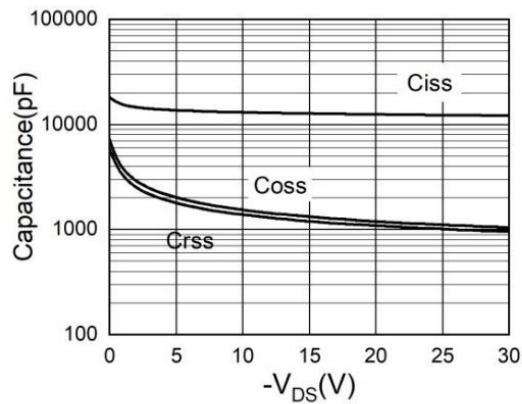


Figure 9. Body-Diode Characteristics

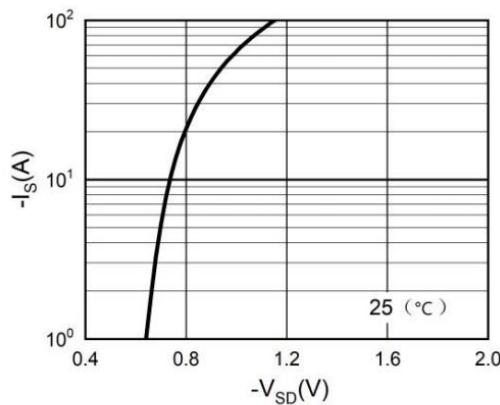
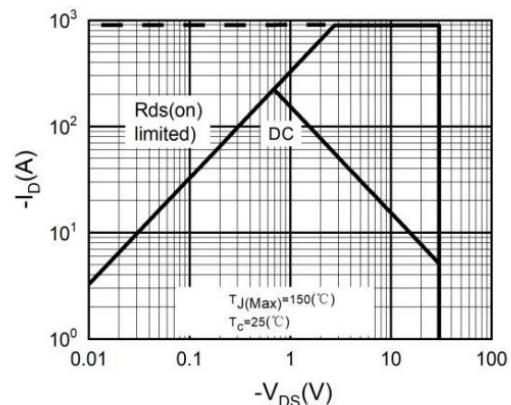
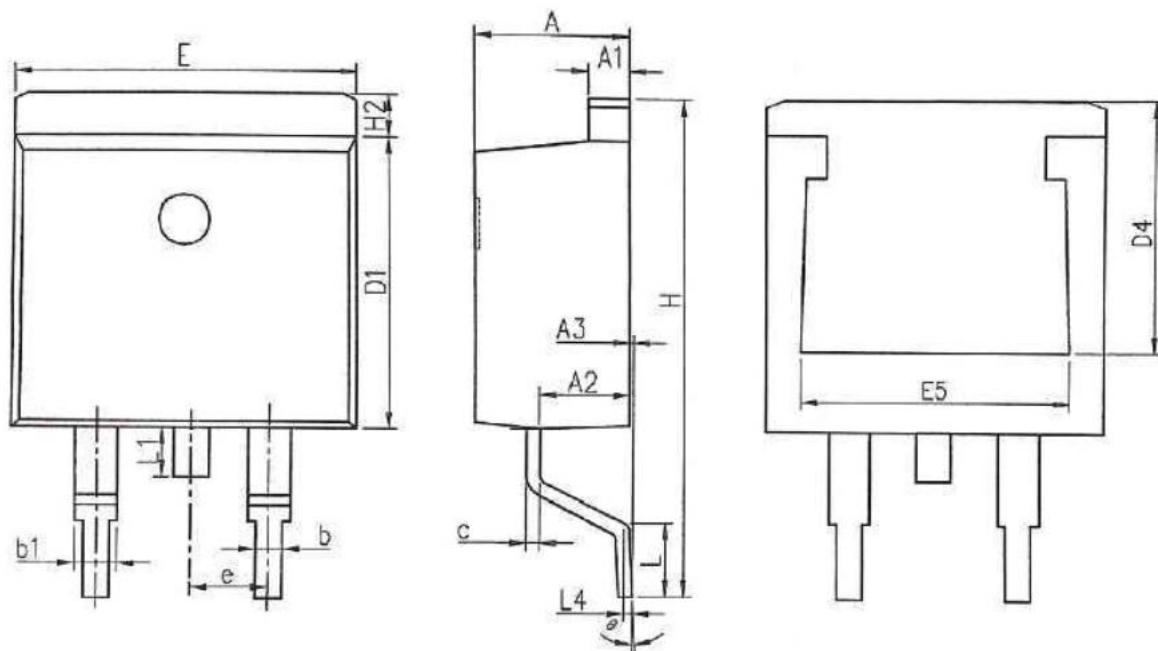


Figure 10. Maximum Safe Operating Area





SYMBOLS	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.370	4.770	0.172	0.188
A1	1.220	1.420	0.048	0.056
A2	2.200	2.890	0.087	0.114
A3	0.000	0.250	0.000	0.010
b	0.700	0.960	0.028	0.038
b1	1.170	1.470	0.046	0.058
c	0.300	0.530	0.012	0.021
D1	8.500	9.300	0.335	0.366
D4	6.600	-	0.260	-
E	9.860	10.36	0.388	0.408
E5	7.060	-	0.278	-
e	2.540 BSC		0.100 BSC	
H	14.70	15.70	0.579	0.618
H2	1.070	1.470	0.042	0.058
L	2.000	2.600	0.079	0.102
L1	1.400	1.750	0.055	0.069
L4	0.250 BSC		0.010 BSC	
$\Theta$	0°	9°	0°	9°